

08-06

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Substitute Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 10559-895001	Application No. 10/799,928
Information Disclosure Statement by Applicant (Use several sheets if necessary) (37 CFR §1.98(b))		Applicant Alexander Tregub et al.	
		Filing Date March 12, 2004	Group Art Unit 1711

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Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
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	AB	2001/0014375	08/2001	Tanaka			
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Examiner Signature /Nathan Nutter/ (12/08/2006)	Date Considered
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	

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Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
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							Yes	No
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Other Documents (include Author, Title, Date, and Place of Publication)		
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NN	BM	Chen, et al., "Pellicle-Induced Reticle Distortion: An Experimental Investigation", <i>Proc. of SPIE - The Int'l Soc. for Optical Engineering</i> , Vol. 3546, pp. 167-172 (1998).
NN	BN	Cotte, et al., "Effects of Soft Pellicle Frame Curvature and Mounting Process on Pellicle-Induced Distortions in Advanced Photomasks", <i>Proc. of SPIE - The Int'l Soc. for Optical Engineering</i> , Vol. 5040, pp. 1044-1054 (2003).
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NN	BR	Oshima, et al., "Chemical structure and physical properties of radiation-induced crosslinking of polytetrafluoroethylene", <i>Radiation Physics and Chemistry</i> , vol. 62, pp.39-45 (2001).
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Other Documents (include Author, Title, Date, and Place of Publication)		
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NN	BU	Van Krevelen, D.W., with the collaboration of P.J. Hoftyzer, <u>Properties of Polymers, Their Estimation and Correlation with Chemical Structure</u> , Elsevier Scientific Publishing Company, Amsterdam – Oxford – New York, pp. 68-73 (1976).

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Substitute Form PTO-1449 (Modified) Information Disclosure Statement by Applicant (Use several sheets if necessary) (37 CFR 51.98(b))	U.S. Department of Commerce Patent and Trademark Office		Attorney's Docket No. 10559-895001	Application No. 10/799,928
	Applicant Alexander Tregub et al.			
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							Yes	No
	AL							
	AM							
	AN							
	AO							
	AP							

Other Documents (include Author, Title, Date, and Place of Publication)		
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	AR	
	AS	
	AT	

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Substitute Disclosure Form (PTO-1449)